



Experiment title:
High pressure synthesis of corundum-type In_2O_3 and new SiC_2N_4 phases

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HS-3413

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ID27

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Report:

Indium oxide

In-situ angle-dispersive X-ray diffraction (AD-XRD) experiments were performed in a diamond anvil cell (DAC) up to ~ 33 GPa. The sol-gel synthesized cubic (bixbyite-type) In_2O_3 was loaded into a cavity of $100 \mu\text{m}$ in diameter and $20\text{-}30 \mu\text{m}$ thickness, drilled in stainless steel gaskets. Pressure was calculated from the equation of state of crystalline argon served as a quasi-hydrostatic pressure medium. Pressure was additionally controlled using the ruby fluorescence method. An *ex-situ* laser heating system (Nd-YAG laser) was used to heat the sample. After heating the samples were quenched to ambient temperature by closing laser shutter. *Unfortunately, it was not possible to perform in-situ heating experiments as it was planned in the proposal.* Focused monochromatic beam ($\lambda=0.3738 \text{ \AA}$) with beam size of approximately $10 \mu\text{m}$ diameter was used at the X-ray source for AD-XRD experiments. The diffraction patterns were collected using MAR-CCD detector and processed with Fit2D (ESRF) and FullProf^[1] software.

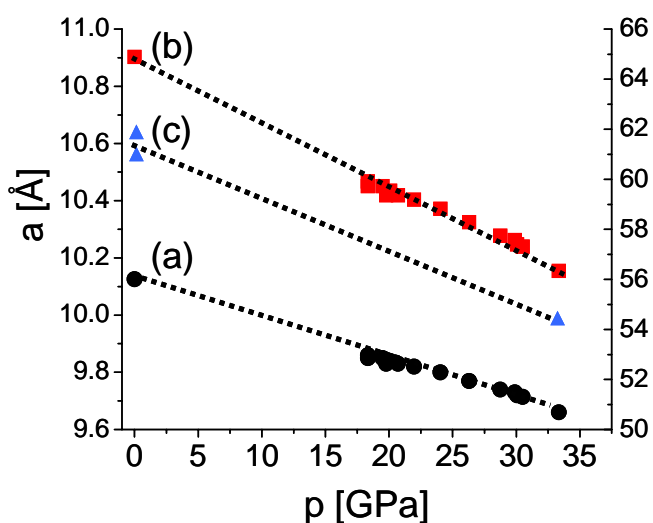


Figure 1. Variation of lattice constant (a) and unit-cell volume (b) with pressure of the c- In_2O_3 in a DAC. The solid lines are shown to guide the eye. (c) Triangles indicate the volume of a new orthorhombic polymorph.

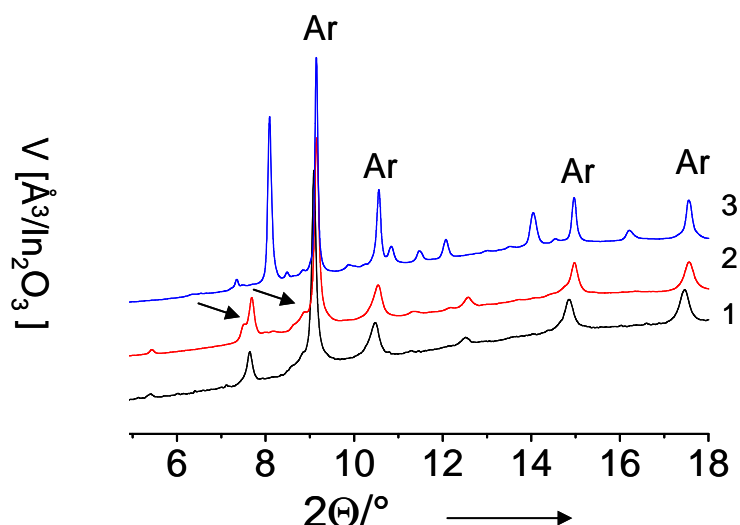


Figure 2. *In-situ* XRD diffraction patterns of c- In_2O_3 in DAC compressed to 33 GPa (1), and after laser-heating (2), (3). "Ar" indicates the reflexes of crystalline argon.

The first remarkable observation is the stability of the *c*-In₂O₃ up to ~33 GPa at RT. The lattice constant decreases by approximately 5% and, accordingly, the volume- by ~15% (Figure 1). Thus, *c*-In₂O₃ is found to be more compressible as compared to other bixbyite-type oxides (see for example, Mn₂O₃^[2]).

A short *ex-situ* laser heating of the compressed (33 GPa) sample induced splitting of the diffraction reflexes, while longer heating (1 min) induced the appearance of a new diffraction pattern (Figure 2). The latter differ significantly from XRD patterns of the *rh*-In₂O₃ compressed to the same pressure (not shown here) as well as of *c*-In₂O₃. Two-dimensional XRD pattern of the compressed laser-heated sample consists of two types of diffraction rings (besides the pattern of compressed argon): (i) almost continuous rings similar to ones observed in the initial powdered sample (i.e. initial *c*-In₂O₃) and (ii) individual spots which appears only in a laser heated sample. The spots, which are characteristic feature of highly textured samples, indicate the crystallisation of several microcrystals of a new phase under high pressure conditions. The sample was recovered to ambient conditions without any changes in the texture

(b). The appearance of two types of diffraction patterns in a laser-heated sample suggested a two phase composition. *c*-In₂O₃ was verified to remain in the sample even after laser-heating. The strong texture causes the variation in diffraction intensities and complicates the full profile Rietveld refinement. Unfortunately the quality of the x-ray diffraction patterns was not sufficient for an unequivocal solving of crystal structure of the new In₂O₃ phase.

The results obtained during our beamtime at the ID27 showed the existence of a new high pressure In₂O₃ polymorph. They call for the reinterpretation of In₂O₃ phase diagram, especially the stability regions of different structures and conditions for their synthesis.

Silicon carbonitride

We also performed high-pressure high-temperature experiments with nanocrystalline silicon-(carbodiimide)-nitride, Si₂CN₄. This Si-C-N phase crystallizes in orthorhombic structure which contain carbodiimide unit (-N=C=N-), i.e. it can be expressed as Si₂N₂(NCN)^[3]. Recent theoretical studies have indicated that -N=C=N- units are unstable on compression and can condensate with Si atoms at high pressures, thus resulting in formation of new denser crystalline Si-C-N phase.^[4] [REF]

The pellets of nanocrystalline Si₂CN₄ powder were loaded in a DAC in argon pressure medium and compressed up to about 20 GPa. The samples were investigated *in-situ* using AD-XRD. The diffraction lines of Si₂CN₄ broaden and weaken considerably with pressure increase, in accordance with earlier high-pressure multi-anvil experiments.^[5] At pressures above 9 GPa the diffraction lines have almost disappeared. We presume that this observation is due to complete amorphization of Si₂CN₄. At maximal pressures of about 20 GPa the samples were annealed *ex-situ* using CO₂-laser. The heating time was very short (10-20 seconds) due to instabilities of stainless steel gaskets. The heating, however, had no effect on the diffraction patterns. The SI-C-N samples recovered to ambient conditions were found to maintain amorphous state.

References

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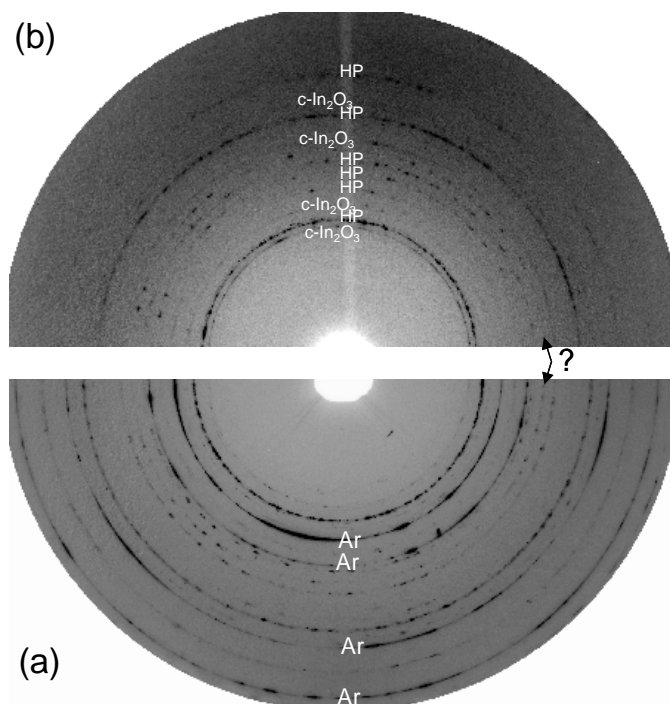


Figure 3. Two dimensional images of laser-heated sample In₂O₃ sample (a) in a DAC at 33 GPa and (b) recovered to ambient conditions.